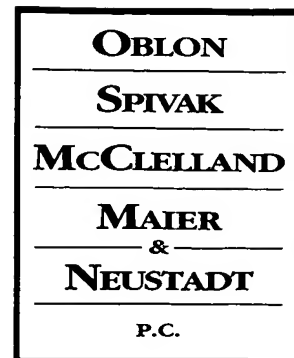




IPW



Docket No.: 245903US2CONT

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

RE: Application Serial No.: 10/717,540
Applicants: Shinichi MURAKAWA, et al.
Filing Date: November 21, 2003
For: APPARATUS AND METHOD FOR TESTING
ELECTRODE STRUCTURE FOR THIN DISPLAY
DEVICE USING FET FUNCTION
Group Art Unit: 2673
Examiner: LEWIS, D.L.

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SIR:

Attached hereto for filing are the following papers:

REQUEST FOR RECONSIDERATION

Our check in the amount of - 0 - is attached covering any required fees. In the event any variance exists between the amount enclosed and the Patent Office charges for filing the above-noted documents, including any fees required under 37 C.F.R. 1.136 for any necessary Extension of Time to make the filing of the attached documents timely, please charge or credit the difference to our Deposit Account No. 15-0030. Further, if these papers are not considered timely filed, then a petition is hereby made under 37 C.F.R. 1.136 for the necessary extension of time. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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DOCKET NO: 245903US2CONT



IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF :
SHINICHI MURAKAWA, ET AL. : EXAMINER: LEWIS, D. L.
SERIAL NO: 10/717,540 :
FILED: NOVEMBER 21, 2003 : GROUP ART UNIT: 2673
FOR: APPARATUS AND METHOD FOR :
TESTING ELECTRODE STRUCTURE
FOR THIN DISPLAY DEVICE USING FET
FUNCTION

REQUEST FOR RECONSIDERATION

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

In response to the Office Action dated December 15, 2005, please note the following
remarks:

Remarks/Arguments begin on page 2 of this paper.